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- **Qualification in Accordance With** AEC-Q100†
- **Qualified for Automotive Applications**
- **Customer-Specific Configuration Control** Can Be Supported Along With Major-Change Approval
- Wide Operating Voltage Range of 2 V to 6 V
- **High-Current 3-State Outputs Interface** Directly With System Bus or Can Drive Up To 15 LSTTL Loads
- Low Power Consumption, 80-µA Max I_{CC}
- Typical $t_{pd} = 11 \text{ ns}$

- ±6-mA Output Drive at 5 V
- Low Input Current of 1 μ A Max

D OR PW PACKAGE (TOP VIEW) 10E 1A 13 1Y 12**П** 4A 20E 11 **∏** 4Y 10 3OE 2A l

4OE

2Y 6 9∏3A Пзү **GND**

description/ordering information

This quadruple bus buffer gate features independent line drivers with 3-state outputs. Each output is disabled when the associated output-enable (\overline{OE}) input is high.

To ensure the high-impedance state during power up or power down, $\overline{\text{OE}}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

ORDERING INFORMATION

TA	PACKAGE [‡]		ORDERABLE PART NUMBER	TOP-SIDE MARKING
-40°C to 85°C	SOIC - D	Reel of 2500	SN74HC125IDRQ1	HC125I
-40°C 10 65°C	TSSOP - PW	Reel of 2000	SN74HC125IPWRQ1	HC125I

[‡] Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

FUNCTION TABLE (each buffer)

INPU	JTS	OUTPUT
OE	Α	Υ
L	Н	Н
L	L	L
Н	Χ	Z

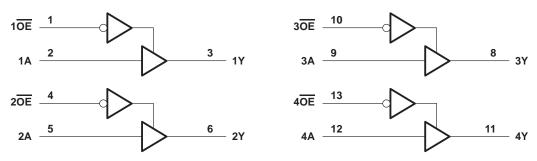


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[†] Contact factory for details. Q100 qualification data available on request.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage range, V _{CC}	\dots -0.5 V to 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (see Note 1)	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$) (see Note 1)	±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±35 mA
Continuous current through V _{CC} or GND	±70 mA
Package thermal impedance, θ _{JA} (see Note 2): D package	86°C/W
PW package	113°C/W
Storage temperature range, T _{stg}	65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51-7.

recommended operating conditions (see Note 3)

			MIN	NOM	MAX	UNIT	
Vcc	Supply voltage		2	5	6	V	
		V _{CC} = 2 V	1.5				
ViH	High-level input voltage	3.15			V		
		VCC = 6 V	4.2				
		V _{CC} = 2 V			0.5		
٧ _{IL}	Low-level input voltage $V_{CC} = 4.5 \text{ V}$				1.35	V	
	High-level input voltage Low-level input voltage Input voltage Output voltage Av Input transition rise/fall time	V _{CC} = 6 V			1.8		
٧ _I	Input voltage		0		VCC	V	
٧o	Output voltage		0		VCC	V	
		V _{CC} = 2 V			1000		
Δt/Δν	· · · · · · · · · · · · · · · · · · ·				500	ns	
V _I I V _O C Δt/Δv I		V _{CC} = 6 V			400		
T _A	Operating free-air temperature		-40		85	°C	

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

24244555	TEGT COMPLETE		Voc	Т	A = 25°C	;				
PARAMETER	TEST CONDITION	ONS	VCC	MIN	TYP	MAX	MIN	MAX	UNIT	
			2 V	1.9	1.998		1.9			
VOH		$I_{OH} = -20 \mu A$	4.5 V	4.4	4.499		4.4			
	VI = VIH or VIL		6 V	5.9	5.999		5.9			
		$I_{OH} = -6 \text{ mA}$	4.5 V	3.98	4.3		3.84			
		$I_{OH} = -7.8 \text{ mA}$	6 V	5.48	5.8		5.34			
		I _{OL} = 20 μA	2 V		0.002	0.1		0.1		
			$I_{OL} = 20 \mu A$	4.5 V		0.001	0.1		0.1	
VOL	VI = VIH or VIL		6 V		0.001	0.1		0.1	V	
		I _{OL} = 6 mA	4.5 V		0.17	0.26		0.33		
	Ī	I _{OL} = 7.8 mA	6 V		0.15	0.26		0.33		
lį	VI = VCC or 0		6 V		±0.1	±100		±1000	nA	
loz	VO = VCC or 0		6 V		±0.01	±0.5		±5	μΑ	
Icc	$V_I = V_{CC}$ or 0,	IO = 0	6 V			8		80	μΑ	
Ci			2 V to 6 V		3	10		10	pF	

switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

DADAMETER	FROM	то	\ \ \	T	ղ = 25°C	;	MIN MAX	MAX	LINUT	
PARAMETER	(INPUT)	(OUTPUT) VCC MIN TYP MAX		MAX	ANIN MIN		UNIT			
			2 V		48	120		150		
t _{pd}	А	Υ	4.5 V		14	24		30	ns	
·			6 V		11	20		26		
			2 V		53	120		150	ns	
t _{en}	ŌĒ	Υ	4.5 V		14	24		30		
			6 V		11	20		26		
			2 V		30	120		150		
^t dis	ŌĒ	Υ	4.5 V		15	24		30	ns	
					14	20		26		
			2 V		28	60	·	75		
t _t		Any	4.5 V		8	12	·	15	15 ns	
			6 V		6	10		13		

SN74HC125-Q1 **QUADRUPLE BUS BUFFER GATE** WITH 3-STATE OUTPUTS SCLS574 - MARCH 2004

switching characteristics over recommended operating free-air temperature range, C_L = 150 pF (unless otherwise noted) (see Figure 1)

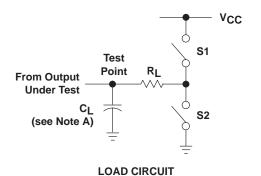
DADAMETED	FROM	то	.,	T	λ = 25°C	;		MAY	
PARAMETER	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	UNIT
			2 V		67	150		190	
^t pd	А	Υ	4.5 V		19	30		38	ns
·			6 V		15	25		32	
			2 V		100	135		170	ns
ten	ŌĒ	Υ	4.5 V		20	27		34	
			6 V		17	23		29	
t _t			2 V		45	210		265	
		Any	4.5 V		17	42		53	ns
			6 V		13	36		45	

operating characteristics, $T_A = 25^{\circ}C$

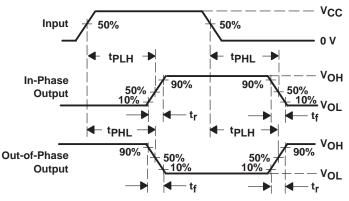
	PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance per gate	No load	45	pF

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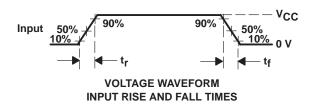
PARAMETER MEASUREMENT INFORMATION

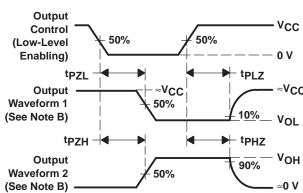


	PARAMETER		RL CL		S1	S2
		^t PZH	1 k Ω	50 pF or	Open	Closed
	t _{en}	tPZL	1 K22	150 pF	Closed	Open
	^t dis	tPHZ	1 k Ω	50 pF	Open	Closed
		tPLZ		30 pr	Closed	Open
	t _{pd} or	t _t		50 pF or 150 pF	Open	Open



VOLTAGE WAVEFORMS
PROPAGATION DELAY AND OUTPUT TRANSITION TIMES





VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES FOR 3-STATE OUTPUTS

NOTES: A. C_L includes probe and test-fixture capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_f = 6 ns, t_f = 6 ns.
- D. The outputs are measured one at a time, with one input transition per measurement.
- E. tpLZ and tpHZ are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

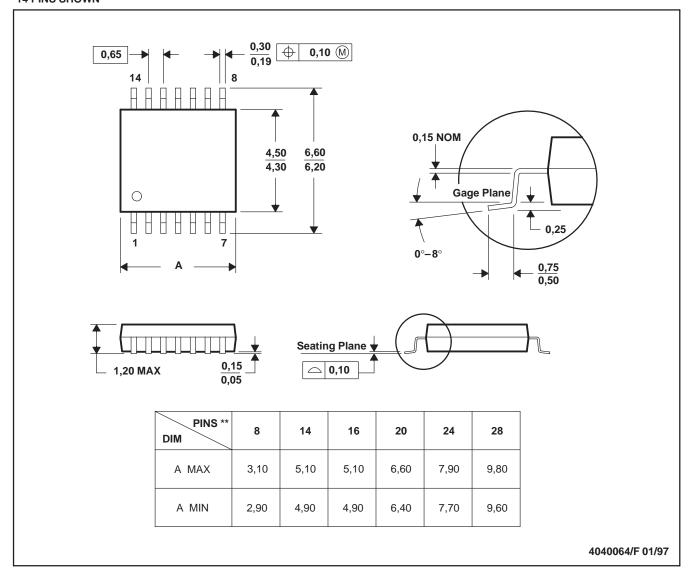
Figure 1. Load Circuit and Voltage Waveforms



PW (R-PDSO-G**)

14 PINS SHOWN

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153

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